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Deep Learning Algorithms and Their Application to Medical Image Analysis

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Deadline for manuscript submissions:

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Message from the Guest Editors

Dear Colleagues,

Medical image analysis serves as a substantial tool to assist radiologists and doctors. Deep learning has been widely used for medical image analysis and has achieved promising performance due to its outstanding automatic feature learning ability. We are witnessing the rapid revolution of deep learning in medical applications, such as computer-aided diagnosis, computer-aided surgery, and radiation therapy. The aim of this Special Issue is to develop novel deep learning algorithms to address medical image analysis problems, such as image registration, anatomical/cell structure detection, tissue segmentation, and disease diagnosis or prognosis. We hope readers that will enjoy this Special Issue and that the articles within will have a significant impact on the field.











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Message from the Editor-in-Chief

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